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INTERNATIONAL STANDARD



Fixed electric double-layer capacitors for use in electric and electronic equipment –

Part 1: Generic specification

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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CONTENTS

Η(OREWO	RD	7
1	Scop	e	9
2	Norm	native references	9
3	Term	s and definitions	10
4		eral items	
•	4.1	Unit and symbols	
	4.2	Preferred values and class	
	4.2.1		
	4.2.2		
	4.2.3	·	
	4.3	Marking	
	4.3.1	General	
	4.3.2		
	4.4	Quality assessment procedures	
5		s and measurement	
-	5.1	General	
	5.2	Test and measurement requirements	
	5.2.1	·	
	5.2.2		
	5.2.3		
	5.2.4	5	
	5.3	Drying	
	5.4	Visual examination and check of dimensions	
	5.4.1		
	5.4.2		
	5.4.3		
	5.5	Measurement method 1 for capacitance and internal resistance (constant	
		current discharge)	16
	5.5.1	Basic circuit for measuring	16
	5.5.2	Measuring equipment	17
	5.5.3	Measuring procedure	18
	5.5.4	Calculation methods for capacitance	20
	5.5.5	Calculation methods for internal resistance	21
	5.5.6	Conditions to be prescribed in the detail specification	22
	5.6	Measurement method 2 for capacitance and internal resistance	22
	5.6.1	Constant resistance charging method for capacitance measurement	22
	5.6.2	AC internal resistance measuring method	23
	5.7	Leakage current	
	5.7.1	Measuring method	23
	5.7.2	·	
	5.8	Maintain voltage	
	5.8.1	Measuring method	
	5.8.2	3	
	5.8.3	·	
	5.9	Robustness of terminations	
	5.9.1	Test Ua1 – Tensile	25

	5.9.2	lest Ub – Bending (half of the sample)	25
	5.9.3	Test Uc – Torsion (remaining sample)	26
	5.9.4	Test Ud – Torque (for terminations with threaded studs or screws and for integral mounting devices)	26
	5.9.5	Visual examination	26
5	.10 Res	istance to soldering heat	26
	5.10.1	Preconditioning and initial measurement	26
	5.10.2	Test	26
	5.10.3	Recovery	26
	5.10.4	Final inspection, measurements and requirements	27
5	.11 Solo	lerability	
	5.11.1	General	
	5.11.2	Preconditioning	
	5.11.3	Capacitors with leads	
	5.11.4	Surface mount capacitors	
5		id change of temperature	
Ī	5.12.1	Initial measurement	
	5.12.2	Test	
	5.12.3	Final inspection, measurements and requirements	
5		ation	
Ŭ	5.13.1	Initial measurement	
	5.13.2	Test	
	5.13.3	Final measurement and requirements	
5		np heat, steady state	
J	5.14.1	Initial measurement	
	5.14.2	Test	
	5.14.3	Final measurement	
_		urance	
U		Initial measurements	
	5.15.1	Test	
	5.15.2 5.15.3		
_		Final measurement, inspection and requirementsage	
O		·	
	5.16.1	Storage at high temperature	
_	5.16.2	Storage at low temperature	
5		racteristics at high and low temperature	
	5.17.1	General	
	5.17.2	Test procedure	
	5.17.3	Dry heat	
	5.17.4	Cold	
	5.17.5	Final measurement and requirements	
5		nponent solvent resistance	
	5.18.1	Initial measurements	
	5.18.2	Test	
	5.18.3	Requirements	
5		rent resistance of marking	
	5.19.1	Test	
	5.19.2	Requirements	
5		sive flammability	
	5 20 1	Test procedure	32

5.20.	2 Requirements	32
5.21	Pressure relief (if applicable)	32
5.21.	1 Test	32
5.21.	2 Requirements	32
Annex A (normative) Classification according to capacitance and internal resistance	33
A.1	General	33
A.2	Classification by capacitance and internal resistance	
Annex B (frequ	informative) Measuring method of capacitance and low resistance by low ency a.c. method (reference)	
B.1	General	35
B.2	Measuring system	35
B.3	Calculation of capacitance	35
B.4	Measuring conditions	36
Annex C (informative) Thermal equilibrium time of capacitors	37
C.1	General	37
C.2	Thermal equilibrium time of capacitors	
_	informative) Charging/discharging efficiency and measurement current	
D.1	General	
D.1 D.2	Charging efficiency, discharging efficiency, and current	
	informative) Procedures for setting the measurement current of capacitor	
with	uncertain nominal internal resistance	41
E.1	General	41
E.2	Current setting procedures for measurement of capacitor	
E.3	Example of setting current for determining capacitor characteristics	
Annex F (informative) Policy on uncertainty of measurement and inset limits	
F.1	Objective	
F.2	Terms and definitions	
F.3	Calculation of measurement uncertainty	
F.4	Policy	
F.5	Calculation of inset and outset limits	
F.6	Examples	
F.6.1	•	
F.6.2		
F.6.3	·	
F.6.4	·	
F.6.5		
	(informative) Reference to IEC 62391-1:2006	
	(normative) Quality assessment procedures	
Q.1	General	46
Q.1.1	Overview	46
Q.1.2	2 Applicability of qualification approval	46
Q.1.3	B Applicability of capability approval	46
Q.1.4		
Q.2	Primary stage of manufacture	47
Q.3	Subcontracting	47
Q.4	Structurally similar components	47
Q.5	Qualification approval procedures	47
Q.5.1	Eligibility for qualification approval	47

0 - 1	2	Application for qualification approval	48
Q.5.3	3	Test procedure for qualification approval	48
Q.5.4	4	Granting of qualification approval	48
Q.5.	5	Maintenance of qualification approval	48
Q.5.6	6	Quality conformance inspection	48
Q.6	Capa	ability approval procedures	48
Q.6.	1	General	
Q.6.2	2	Eligibility for capability approval	49
Q.6.3	3	Application for capability approval	49
Q.6.4	4	Description of capability	49
Q.6.	5	Demonstration and verification of capability	50
Q.6.6	6	Programme for capability approval	50
Q.6.	7	Capability approval test report	51
Q.6.8	8	Abstract of description of capability	51
Q.6.9	9	Modifications likely to affect the capability approval	51
Q.6.	10	Initial capability approval	
Q.6.	11	Granting of capability approval	
Q.6.	12	Maintenance of capability approval	52
Q.6.	13	Extension of capability approval	53
Q.6.	14	Quality conformance inspection	53
Q.7	Rew	ork and repair	53
Q.7.	1	Rework	53
Q.7.2	2	Repair	54
Q.8	Rele	ase for delivery	
Q.8.	1	General	54
Q.8.2	2	Release for delivery under qualification approval before the completion of Group B tests	54
Q.9	Cert	ified test records of released lots	54
Q.9 Q.10		ified test records of released lotsyed delivery	
	Dela Alter	yed delivery native test methods	54 54
Q.10	Dela Alter Man	yed delivery native test methodsufacture outside the geographical limits of IECQ CBs	54 54 54
Q.10 Q.11 Q.12 Q.13	Dela Alter Man Unch	yed delivery native test methodsufacture outside the geographical limits of IECQ CBs necked parameters	54 54 54
Q.10 Q.11 Q.12 Q.13 Q.14	Dela Alter Man Unch Tech	yed delivery native test methods ufacture outside the geographical limits of IECQ CBs necked parameters nnology approval procedures	54 54 54 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14	Dela Alter Man Unch Tech	yed delivery	54 54 54 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech	yed delivery rnative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nnology approval procedures General Eligibility for technology approval	54 54 54 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1.1 4.2	yed delivery native test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval	54 54 54 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1.1 1.2 1.3	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology Description of technology	54 54 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech .1 .2 .3 3	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology	54 54 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1.1 1.2 1.3 1.4 1.5	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval	54 54 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1 2 3 4 5 6	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval	54 54 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1.1 1.2 1.3 1.4 1.5 1.6 1.7	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval Quality conformance inspection	54 54 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech .1 .2 .3 .4 .5 .6 .7	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval Quality conformance inspection Failure rate level determination	54 54 55 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1 2 3 4 5 6 7 8 8 9	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval Quality conformance inspection Failure rate level determination Outgoing quality level	54 54 55 55 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1 2 3 4 5 6 7 8 8 9	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval Quality conformance inspection Failure rate level determination	54 54 55 55 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1 2 3 4 5 6 7 8 8 9	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval Quality conformance inspection Failure rate level determination Outgoing quality level	54 54 55 55 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14	Dela Alter Man Unch Tech 1.1 1.2 1.3 1.4 1.5 1.6 1.7 1.8 1.9 1.10 1.10	yed delivery mative test methods ufacture outside the geographical limits of IECQ CBs necked parameters nology approval procedures General Eligibility for technology approval Application of technology approval Description of technology Demonstration and verification of the technology Granting of technology approval Maintenance of technology approval Quality conformance inspection Failure rate level determination Outgoing quality level	54 54 55 55 55 55 55 55 55 55
Q.10 Q.11 Q.12 Q.13 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 Q.14 G.14 G.14 G.14 G.14 Figure 1 -	Dela Alter Man Unch .1 .2 .3 .4 .5 .6 .7 .8 .9 .10 ohy	yed delivery	54545555555555555555

Figure 4 - Circuit for a.c. resistance method	23
Figure 5 - Maintain voltage test diagram	24
Figure A.1 – Conceptual rendering orientated by characteristics in each classification	34
Figure B.1 – Capacitance measuring system by the low frequency a.c. method	35
Figure C.1 – Thermal equilibrium times of capacitors (from 85 °C to 25 °C)	37
Figure C.2 – Thermal equilibrium times of capacitors (from −40 °C to 25 °C)	38
Figure C.3 – Capacitor core temperature change with respect to time	38
Figure Q.1 – General scheme for capability approval	49
Table 1 – Measuring conditions for measuring method 1A	19
Table 2 – Measuring conditions for measuring method 1B	20
Table 3 – Tensile force	25
Table 4 – Torque	26
Table 5 – Severities and requirements	32
Table A.1 – Electrical performance and measuring method by class	34
Table E.1 – Example of setting current for measurement of capacitor	41

INTERNATIONAL ELECTROTECHNICAL COMMISSION

FIXED ELECTRIC DOUBLE-LAYER CAPACITORS FOR USE IN ELECTRIC AND ELECTRONIC EQUIPMENT –

Part 1: Generic specification

FOREWORD

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International Standard IEC 62391-1 has been prepared by IEC technical committee 40: Capacitors and resistors for electronic equipment.

This second edition cancels and replaces the first edition published in 2006 and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) enhancement of the scope to include electric (high power) application;
- b) implementation of Annex Q, replacing Clause 3 in the first edition;
- c) in addition, minor revisions related to tables, figures and references.

The text of this standard is based on the following documents:

FDIS	Report on voting
40/2393/FDIS	40/2415/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 62391 under the general title *Fixed electric double-layer capacitors for use in electric and electronic equipment* can be found in the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed.
- · withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

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FIXED ELECTRIC DOUBLE-LAYER CAPACITORS FOR USE IN ELECTRIC AND ELECTRONIC EQUIPMENT -

Part 1: Generic specification

1 Scope

This part of IEC 62391 applies to fixed electric double-layer capacitors (hereafter referred to as capacitor(s)) mainly used in d.c. circuits of electric and electronic equipment.

This part of IEC 62391 establishes standard terms, inspection procedures and methods of test for use in sectional and detail specifications of electronic components for quality assessment or any other purpose.

2 Normative references

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), Letter symbols to be used in electrical technology

IEC 60050 (all parts), International Electrotechnical Vocabulary

IEC 60062, Marking codes for resistors and capacitors

IEC 60063, Preferred number series for resistors and capacitors

IEC 60068-1:2013, Environmental testing – Part 1: General and guidance

IEC 60068-2-1:2007, Environmental testing – Part 2-1: Tests – Tests A: Cold

IEC 60068-2-2:2007, Environmental testing – Part 2-2: Tests – Tests B: Dry Heat

IEC 60068-2-6:2007, Environmental testing – Part 2-6: Tests – Test Fc: Vibration (sinusoidal)

IEC 60068-2-14:2009, Environmental testing – Part 2-14: Tests – Test N: Change of temperature

IEC 60068-2-20:2008, Environmental testing – Part 2-20: Tests – Test T: Test methods for solderability and resistance to soldering heat of devices of with leads

IEC 60068-2-21:2006, Environmental testing – Part 2-21: Tests – Test U: Robustness of terminations and integral mounting devices

IEC 60068-2-45:1980, Environmental testing – Part 2-45: Tests – Test XA and guidance: Immersion in cleaning solvents
Amendment 1:1993)

IEC 60068-2-54:2006, Environmental testing – Part 2-54: Tests – Test Ta: Solderbility testing of electronic components by the wetting balance method

IEC 60068-2-58:2015, Environmental testing – Part 2-58: Tests – Test Td: Test methods for solderability, resistance to dissolution of metallization and to soldering heat of surface mounting devices (SMD)

IEC 60068-2-69:2007, Environmental testing – Part 2-69: Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method

IEC 60068-2-78:2012, Environmental testing – Part 2-78: Tests – Test Cab: Damp heat, steady state

IEC 60294:2012, Measurement of the dimensions of a cylindrical component with axial terminations

IEC 60617 (all parts), Graphical symbols for diagrams

IEC 60695-11-5, Fire hazard testing – Part 11-5: Test flames – Needle-flame test method – Apparatus, confirmatory test arrangement and guidance

IEC 60717:2012, Method for the determination of the space required by capacitors and resistors with unidirectional terminations

IEC 61193-2, Quality assessment systems – Part 2: Selection and use of sampling plans for inspection of electronic components and packages